Measuring Anisotropy in Microwave Substrates

M. Olyphant, Jr.. "Measuring Anisotropy in Microwave Substrates." 1979 MTT-S International Microwave Symposium Digest 79.1 (1979 [MWSYM]): 91-93.

A split TE/sub 111/ cavity is described which enables the accurate measurement of the within-plane dielectric constant of a 1 inch disk cut from substrates in the range 25 to 125 mils in thickness. HP 67/97 programs are included for both end and center located specimens.

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